EXTREME SURFACE

1nm

New equipment ToF-SIMS

A ToF-SIMS analysis is an extreme surface analysis technique using mass spectroscopy to identify the chemical components of a material at the nanoscale. This technique offers high resolution, high sensitivity and allows detailed analysis of the sample surface.

Our state-of-the-art equipment allows

- identify the composition of a surface pollution
- determine precisely the origin of the failure.
- validate the integrity of a surface treatment or functionalisation

FEATURES IONTOF M6

- Information depth of 1 nm
- High spatial resolution (up to 50 nm)
- Atomic and molecular identification
- High sensitivity down to the PPM
- For all types of materials (even hard ones)
- Argon aggregate profiling
- Thickness profiling and multilayer profiling
- 3D mapping
- 45° FIB section
- Great versatility

Control of the equipment,
Interpretation of results
Accompaniment towards the solution

Efficiency, Quality, Solution

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MATERIA NOVA Materials R&D Center

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